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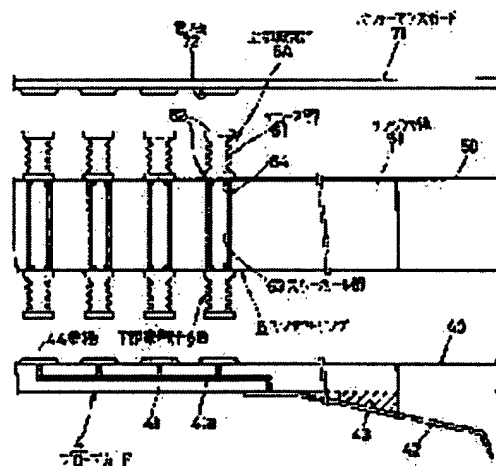
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(54) PROBER

(57)Abstract:

PURPOSE: To provide a probe with uniform electrical resistance between electrodes used in measurement, by making electrical resistance smaller between the probe-card electrode and test-head electrode.

CONSTITUTION: An upper contact member 6A and a lower contact member 6B includes each bellows part 61 elastic in a cross-sectional direction of a contact ring 5 and each terminal sleeve 62 at both ends of the bellows part 61. The upper and lower contact members 6A and 6B are provided at the upper and lower ends of the contact ring 5, as an intermediate connection body, in accordance with a configuration of an electrode 72 in a test head 7 and an electrode 44 is a probe card 4. At the same time, the upper and lower contact members 6A and 6B are connected electrically through a through hole 63 provided in a ring body 51. These contact members 6A and 6B are each pushed steadily in contact with the electrodes 72 and 44 through restoring force of the bellows part 61 so that the probe card 4 and the test head 7 are connected electrically.



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